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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	50MHz
Connectivity	I ² C, IrDA, SPI, UART/USART, USB, USB OTG
Peripherals	DMA, I ² S, LVD, POR, PWM, WDT
Number of I/O	64
Program Memory Size	256КВ (256К х 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 20x16b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	121-LFBGA
Supplier Device Package	121-MAPBGA (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mk21dx256avmc5

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



ran identification

Field	Description	Values
FFF	Program flash memory size	 32 = 32 KB 64 = 64 KB 128 = 128 KB 256 = 256 KB 512 = 512 KB 1M0 = 1 MB 2M0 = 2 MB
R	Silicon revision	 Z = Initial (Blank) = Main A = Revision after main
Т	Temperature range (°C)	 V = -40 to 105 C = -40 to 85
PP	Package identifier	 FM = 32 QFN (5 mm x 5 mm) FT = 48 QFN (7 mm x 7 mm) LF = 48 LQFP (7 mm x 7 mm) LH = 64 LQFP (10 mm x 10 mm) MP = 64 MAPBGA (5 mm x 5 mm) LK = 80 LQFP (12 mm x 12 mm) LL = 100 LQFP (14 mm x 14 mm) MC = 121 MAPBGA (8 mm x 8 mm) LQ = 144 LQFP (20 mm x 20 mm) MD = 144 MAPBGA (13 mm x 13 mm)
СС	Maximum CPU frequency (MHz)	 5 = 50 MHz 7 = 72 MHz 10 = 100 MHz 12 = 120 MHz 15 = 150 MHz 18 = 180 MHz
Ν	Packaging type	 R = Tape and reel (Blank) = Trays

2.4 Example

This is an example part number:

MK21DX128VLK5

2.5 Small package marking

In an effort to save space, small package devices use special marking on the chip. These markings have the following format:

Q ## C F T PP

This table lists the possible values for each field in the part number for small packages (not all combinations are valid):



reminology and guidelines

3.2 Definition: Operating behavior

An *operating behavior* is a specified value or range of values for a technical characteristic that are guaranteed during operation if you meet the operating requirements and any other specified conditions.

3.2.1 Example

This is an example of an operating behavior:

Symbol	Description	Min.	Max.	Unit
1 ···	Digital I/O weak pullup/ pulldown current	10	130	μΑ

3.3 Definition: Attribute

An *attribute* is a specified value or range of values for a technical characteristic that are guaranteed, regardless of whether you meet the operating requirements.

3.3.1 Example

This is an example of an attribute:

Symbol	Description	Min.	Max.	Unit
CIN_D	Input capacitance: digital pins	_	7	pF

3.4 Definition: Rating

A *rating* is a minimum or maximum value of a technical characteristic that, if exceeded, may cause permanent chip failure:

- Operating ratings apply during operation of the chip.
- Handling ratings apply when the chip is not powered.



4.2 Moisture handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
MSL	Moisture sensitivity level	_	3	—	1

1. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

4.3 ESD handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
V _{HBM}	Electrostatic discharge voltage, human body model	-2000	+2000	V	1
V _{CDM}	Electrostatic discharge voltage, charged-device model	-500	+500	V	2
I _{LAT}	Latch-up current at ambient temperature of 105°C	-100	+100	mA	3

- 1. Determined according to JEDEC Standard JESD22-A114, *Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)*.
- 2. Determined according to JEDEC Standard JESD22-C101, Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components.
- 3. Determined according to JEDEC Standard JESD78, IC Latch-Up Test.

4.4 Voltage and current operating ratings

Symbol	Description	Min.	Max.	Unit
V _{DD}	Digital supply voltage	-0.3	3.8	V
I _{DD}	Digital supply current	_	155	mA
V _{DIO}	Digital input voltage (except RESET, EXTAL, and XTAL)	-0.3		V
V _{AIO}	Analog ¹ , RESET, EXTAL, and XTAL input voltage	-0.3	V _{DD} + 0.3	V
Ι _D	Maximum current single pin limit (applies to all digital pins)	-25	25	mA
V _{DDA}	Analog supply voltage	V _{DD} – 0.3	V _{DD} + 0.3	V
V _{USB0_DP}	USB0_DP input voltage	-0.3	3.63	V
V _{USB0_DM}	USB0_DM input voltage	-0.3	3.63	V
VREGIN	USB regulator input	-0.3	6.0	V
V _{BAT}	RTC battery supply voltage	-0.3	3.8	V

1. Analog pins are defined as pins that do not have an associated general purpose I/O port function.

5 General



Notes

1. Rising threshold is the sum of falling threshold and hysteresis voltage

Symbol	Description	Min.	Тур.	Max.	Unit	l
V _{POR_VBAT}	Falling VBAT supply POR detect voltage	0.8	1.1	1.5	V	

Table 3. VBAT power operating requirements

5.2.3 Voltage and current operating behaviors Table 4. Voltage and current operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
V _{OH}	Output high voltage — high drive strength				
	• 2.7 V \leq V _{DD} \leq 3.6 V, I _{OH} = - 9 mA	V _{DD} – 0.5	_	V	
	• 1.71 V \leq V _{DD} \leq 2.7 V, I _{OH} = -3 mA	V _{DD} – 0.5	_	v	
	Output high voltage — low drive strength				
	• 2.7 V \leq V _{DD} \leq 3.6 V, I _{OH} = -2 mA	V _{DD} – 0.5	_	v	
	• 1.71 V \leq V _{DD} \leq 2.7 V, I _{OH} = -0.6 mA	V _{DD} – 0.5	_	v	
I _{OHT}	Output high current total for all ports	_	100	mA	
V _{OL}	Output low voltage — high drive strength				
	• 2.7 V \leq V _{DD} \leq 3.6 V, I _{OL} = 9 mA	_	0.5	V	
	• 1.71 V \leq V _{DD} \leq 2.7 V, I _{OL} = 3 mA	_	0.5	v	
	Output low voltage — low drive strength				
	• 2.7 V \leq V _{DD} \leq 3.6 V, I _{OL} = 2 mA	_	0.5	v	
	• 1.71 V \leq V _{DD} \leq 2.7 V, I _{OL} = 0.6 mA	_	0.5	v	
I _{OLT}	Output low current total for all ports	_	100	mA	
I _{IN}	Input leakage current (per pin)				
	@ full temperature range	—	1.0	μΑ	1
	• @ 25 °C	_	0.1	μΑ	
I _{OZ}	Hi-Z (off-state) leakage current (per pin)	—	1	μA	
I _{OZ}	Total Hi-Z (off-state) leakage current (all input pins)	_	4	μΑ	
R _{PU}	Internal pullup resistors	22	50	kΩ	2
R _{PD}	Internal pulldown resistors	22	50	kΩ	3

1. Tested by ganged leakage method

- 2. Measured at Vinput = V_{SS}
- 3. Measured at Vinput = V_{DD}



Symbol	Description	Min.	Тур.	Max.	Unit	Notes
I _{DD_RUN}	Run mode current — all peripheral clocks enabled, code executing from flash					3, 4
	• @ 1.8 V		17.04	19.3	mA	
	• @ 3.0 V		17.04	10.0		
	• @ 25°C	_	17.01	18.9	mA	
	• @ 125°C		19.8	21.3	mA	
I _{DD_WAIT}	Wait mode high frequency current at 3.0 V — all peripheral clocks disabled	_	7.95	9.5	mA	2
I _{DD_WAIT}	Wait mode reduced frequency current at 3.0 V — all peripheral clocks disabled	_	5.88	7.4	mA	5
I _{DD_STOP}	Stop mode current at 3.0 V	_	320	436	μA	
	 @ −40 to 25°C @ 50°C 		360	489		
	• @ 70°C		410	620		
	• @ 105°C		610	1100		
I _{DD_VLPR}	Very-low-power run mode current at 3.0 V — all peripheral clocks disabled	_	754		μA	6
I _{DD_VLPR}	Very-low-power run mode current at 3.0 V — all peripheral clocks enabled	_	1.1		mA	7
I _{DD_VLPW}	Very-low-power wait mode current at 3.0 V	—	437	_	μA	8
I _{DD_VLPS}	Very-low-power stop mode current at 3.0 V	—	7.33	24.2	μA	
	 @ −40 to 25°C @ 50°C 		14	32		
	• @ 70°C • @ 105°C		28	48		
			110	280		
I _{DD_LLS}	Low leakage stop mode current at 3.0 V		3.14	4.8	μA	
	 @ -40 to 25°C @ 50°C 		6.48	28.3		
	• @ 70°C		13.85	44.6		
	• @ 105°C		55.53	71.3		
I _{DD_VLLS3}	Very low-leakage stop mode 3 current at 3.0 V	_	2.19	3.4	μA	
	• @ -40 to 25°C		4.35	4.35		
	• @ 50°C • @ 70°C		8.92	24.6		
	• @ 105°C		35.33	45.3		
I _{DD_VLLS2}	Very low-leakage stop mode 2 current at 3.0 V	_	1.77	3.1	μA	
	 @ −40 to 25°C @ 50°C 		2.81	13.8		
	• @ 70°C		5.20	22.3		
	• @ 105°C		19.88	34.2		

Table 6. Power consumption operating behaviors (continued	Table 6.	Power	consumption	operating	behaviors	(continued)
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- 3. $V_{DD} = 3.3 \text{ V}, T_A = 25 \text{ °C}, f_{OSC} = 12 \text{ MHz} \text{ (crystal)}, f_{SYS} = 48 \text{ MHz}, f_{BUS} = 48 \text{ MHz}$
- 4. Specified according to Annex D of IEC Standard 61967-2, Measurement of Radiated Emissions TEM Cell and Wideband TEM Cell Method

5.2.7 Designing with radiated emissions in mind

To find application notes that provide guidance on designing your system to minimize interference from radiated emissions:

- 1. Go to www.freescale.com.
- 2. Perform a keyword search for "EMC design."

5.2.8 Capacitance attributes

Table 8. Capacitance attributes

Symbol	Description	Min.	Max.	Unit
C _{IN_A}	Input capacitance: analog pins	—	7	pF
C _{IN_D}	Input capacitance: digital pins	—	7	pF

5.3 Switching specifications

5.3.1 Device clock specifications

Table 9. Device clock specifications

Symbol	Description	Min.	Max.	Unit	Notes
	Normal run mode	9			
f _{SYS}	System and core clock	—	50	MHz	
	System and core clock when Full Speed USB in operation	20	_	MHz	
f _{BUS}	Bus clock	—	50	MHz	
f _{FLASH}	Flash clock	—	25	MHz	
f _{LPTMR}	LPTMR clock	—	25	MHz	
	VLPR mode ¹				
f _{SYS}	System and core clock	_	4	MHz	
f _{BUS}	Bus clock	—	4	MHz	
f _{FLASH}	Flash clock	—	1	MHz	
f _{ERCLK}	External reference clock	—	16	MHz	
f _{LPTMR_pin}	LPTMR clock	_	25	MHz	



Symbol	Description	Min.	Max.	Unit	Notes
f _{LPTMR_ERCLK}	LPTMR external reference clock	—	16	MHz	
f _{I2S_MCLK}	I2S master clock	—	12.5	MHz	
f _{I2S_BCLK}	I2S bit clock		4	MHz	

Table 9. Device clock specifications (continued)

1. The frequency limitations in VLPR mode here override any frequency specification listed in the timing specification for any other module.

5.3.2 General switching specifications

These general purpose specifications apply to all pins configured for:

- GPIO signaling
- Other peripheral module signaling not explicitly stated elsewhere

Table 10. General switching specifications

Symbol	Description	Min.	Max.	Unit	Notes
	GPIO pin interrupt pulse width (digital glitch filter disabled) — Synchronous path	1.5	-	Bus clock cycles	1, 2
	GPIO pin interrupt pulse width (digital glitch filter disabled, analog filter enabled) — Asynchronous path	100	-	ns	3
	GPIO pin interrupt pulse width (digital glitch filter disabled, analog filter disabled) — Asynchronous path	50	-	ns	3
	External reset pulse width (digital glitch filter disabled)	100	_	ns	3
	Port rise and fall time (high drive strength)				4
	Slew disabled				
	• $1.71 \le V_{DD} \le 2.7V$	—	13	ns	
	• $2.7 \le V_{DD} \le 3.6V$	_	7	ns	
	Slew enabled				
	• 1.71 ≤ V _{DD} ≤ 2.7V	_	36	ns	
	• $2.7 \le V_{DD} \le 3.6V$	—	24	ns	
	Port rise and fall time (low drive strength)				5
	Slew disabled				
	• $1.71 \le V_{DD} \le 2.7V$	_	12	ns	
	• $2.7 \le V_{DD} \le 3.6V$	_	6	ns	
	Slew enabled				
	• $1.71 \le V_{DD} \le 2.7V$	_	36	ns	
	• $2.7 \le V_{DD} \le 3.6V$	_	24	ns	

- 1. This is the minimum pulse width that is guaranteed to pass through the pin synchronization circuitry. Shorter pulses may or may not be recognized. In Stop, VLPS, LLS, and VLLSx modes, the synchronizer is bypassed so shorter pulses can be recognized in that case.
- 2. The greater synchronous and asynchronous timing must be met.

K21 Sub-Family Data Sheet, Rev. 4.1, 08/2013.



- 3. This is the minimum pulse width that is guaranteed to be recognized as a pin interrupt request in Stop, VLPS, LLS, and VLLSx modes.
- 4. 75 pF load
- 5. 15 pF load

5.4 Thermal specifications

5.4.1 Thermal operating requirements

Table 11. Thermal operating requirements

Symbol	Description	Min.	Max.	Unit
TJ	Die junction temperature	-40	125	°C
T _A	Ambient temperature	-40	105	°C

5.4.2 Thermal attributes

Board type	Symbol	Description	80 LQFP	Unit	Notes
Single-layer (1s)	R _{0JA}	Thermal resistance, junction to ambient (natural convection)	50	°C/W	1,2
Four-layer (2s2p)	R _{0JA}	Thermal resistance, junction to ambient (natural convection)	35	°C/W	1, 3
Single-layer (1s)	R _{ejma}	Thermal resistance, junction to ambient (200 ft./ min. air speed)	39	°C/W	1,3
Four-layer (2s2p)	R _{ejma}	Thermal resistance, junction to ambient (200 ft./ min. air speed)	29	°C/W	1,3
-	R _{θJB}	Thermal resistance, junction to board	19	°C/W	4
—	R _{θJC}	Thermal resistance, junction to case	8	°C/W	5

Table continues on the next page...

K21 Sub-Family Data Sheet, Rev. 4.1, 08/2013.



Symbol	Description	Min.	Тур.	Max.	Unit	Notes
V _{DD}	Supply voltage	1.71	_	3.6	V	
IDDOSC	Supply current — low-power mode (HGO=0)					1
	• 32 kHz	_	500	_	nA	
	• 4 MHz	_	200	_	μA	
	• 8 MHz (RANGE=01)	_	300	_	μA	
	• 16 MHz	_	950	_	μA	
	• 24 MHz	_	1.2	_	mA	
	• 32 MHz	_	1.5	_	mA	
I _{DDOSC}	Supply current — high-gain mode (HGO=1)					1
	• 32 kHz	_	25	—	μA	
	• 4 MHz	_	400	_	μA	
	• 8 MHz (RANGE=01)	_	500	_	μA	
	• 16 MHz	_	2.5	_	mA	
	• 24 MHz	_	3	_	mA	
	• 32 MHz	_	4	—	mA	
C _x	EXTAL load capacitance	_		_		2, 3
Cy	XTAL load capacitance		—	—		2, 3
R _F	Feedback resistor — low-frequency, low-power mode (HGO=0)	_	—	—	MΩ	2, 4
	Feedback resistor — low-frequency, high-gain mode (HGO=1)	—	10	—	MΩ	-
	Feedback resistor — high-frequency, low-power mode (HGO=0)	—		—	MΩ	-
	Feedback resistor — high-frequency, high-gain mode (HGO=1)	—	1	—	MΩ	-
R _S	Series resistor — low-frequency, low-power mode (HGO=0)	—	_	—	kΩ	
	Series resistor — low-frequency, high-gain mode (HGO=1)	_	200	—	kΩ	
	Series resistor — high-frequency, low-power mode (HGO=0)	—	_	—	kΩ	
	Series resistor — high-frequency, high-gain mode (HGO=1)					
		_	0		kΩ	

6.3.2.1 Oscillator DC electrical specifications Table 15. Oscillator DC electrical specifications



4. Crystal startup time is defined as the time between oscillator being enabled and OSCINIT bit in the MCG_S register being set.

NOTE

The 32 kHz oscillator works in low power mode by default and cannot be moved into high power/gain mode.

6.3.3 32 kHz oscillator electrical characteristics

6.3.3.1 32 kHz oscillator DC electrical specifications Table 17. 32kHz oscillator DC electrical specifications

Symbol	Description	Min.	Тур.	Max.	Unit
V _{BAT}	Supply voltage	1.71	_	3.6	V
R _F	Internal feedback resistor	_	100	_	MΩ
C _{para}	Parasitical capacitance of EXTAL32 and XTAL32		5	7	pF
V _{pp} ¹	Peak-to-peak amplitude of oscillation		0.6		V

1. When a crystal is being used with the 32 kHz oscillator, the EXTAL32 and XTAL32 pins should only be connected to required oscillator components and must not be connected to any other devices.

6.3.3.2 32 kHz oscillator frequency specifications Table 18. 32 kHz oscillator frequency specifications

Symbol	Description	Min.	Тур.	Max.	Unit	Notes
f _{osc_lo}	Oscillator crystal	—	32.768	—	kHz	
t _{start}	Crystal start-up time	—	1000	_	ms	1
V _{ec_extal32}	Externally provided input clock amplitude	700	_	V_{BAT}	mV	2, 3

1. Proper PC board layout procedures must be followed to achieve specifications.

This specification is for an externally supplied clock driven to EXTAL32 and does not apply to any other clock input. The
oscillator remains enabled and XTAL32 must be left unconnected.

3. The parameter specified is a peak-to-peak value and V_{IH} and V_{IL} specifications do not apply. The voltage of the applied clock must be within the range of V_{SS} to V_{BAT} .

6.4 Memories and memory interfaces

6.4.1 Flash electrical specifications

This section describes the electrical characteristics of the flash memory module.



Symbol	Description	Min.	Тур.	Max.	Unit	Notes
	Swap Control execution time					
t _{swapx01}	control code 0x01	—	200	_	μs	
t _{swapx02}	control code 0x02	—	70	150	μs	
t _{swapx04}	control code 0x04	—	70	150	μs	
t _{swapx08}	control code 0x08	—	_	30	μs	
	Program Partition for EEPROM execution time					
t _{pgmpart64k}	64 KB FlexNVM	—	138	_	ms	
	Set FlexRAM Function execution time:					
t _{setramff}	Control Code 0xFF	—	70	—	μs	
t _{setram32k}	32 KB EEPROM backup	—	0.8	1.2	ms	
t _{setram64k}	64 KB EEPROM backup	—	1.3	1.9	ms	
	Byte-write to FlexRAM	for EEPRON	l operation		I	
t _{eewr8bers}	Byte-write to erased FlexRAM location execution time	—	175	260	μs	3
	Byte-write to FlexRAM execution time:					
t _{eewr8b32k}	32 KB EEPROM backup	—	385	1800	μs	
t _{eewr8b64k}	64 KB EEPROM backup		475	2000	μs	
	Word-write to FlexRAM	for EEPRON	I operation	I	ł	ł
t _{eewr16bers}	Word-write to erased FlexRAM location execution time	—	175	260	μs	
	Word-write to FlexRAM execution time:					
t _{eewr16b32k}	32 KB EEPROM backup	—	385	1800	μs	
t _{eewr16b64k}	64 KB EEPROM backup	—	475	2000	μs	
	Longword-write to FlexRA	M for EEPR	OM operation	י ו		
t _{eewr32bers}	Longword-write to erased FlexRAM location execution time	—	360	540	μs	
	Longword-write to FlexRAM execution time:					
t _{eewr32b32k}	32 KB EEPROM backup	—	630	2050	μs	
t _{eewr32b64k}	64 KB EEPROM backup	—	810	2250	μs	

Table 20. Flash command timing specifications (continued)

1. Assumes 25 MHz flash clock frequency.

2. Maximum times for erase parameters based on expectations at cycling end-of-life.

3. For byte-writes to an erased FlexRAM location, the aligned word containing the byte must be erased.



6.5.1 Drylce Tamper Electrical Specifications

Information about security-related modules is not included in this document and is available only after a nondisclosure agreement (NDA) has been signed. To request an NDA, please contact your local Freescale sales representative.

6.6 Analog

6.6.1 ADC electrical specifications

The 16-bit accuracy specifications listed in Table 24 and Table 25 are achievable on the differential pins ADCx_DP0, ADCx_DM0.

All other ADC channels meet the 13-bit differential/12-bit single-ended accuracy specifications.

Symbol	Description	Conditions	Min.	Typ. ¹	Max.	Unit	Notes
V _{DDA}	Supply voltage	Absolute	1.71	—	3.6	V	
ΔV_{DDA}	Supply voltage	Delta to V _{DD} (V _{DD} – V _{DDA})	-100	0	+100	mV	2
ΔV_{SSA}	Ground voltage	Delta to V _{SS} (V _{SS} – V _{SSA})	-100	0	+100	mV	2
V _{REFH}	ADC reference voltage high		1.13	V _{DDA}	V _{DDA}	V	
V _{REFL}	ADC reference voltage low		V _{SSA}	V _{SSA}	V _{SSA}	V	
V _{ADIN}	Input voltage	16-bit differential mode	VREFL	—	31/32 * VREFH	V	
		All other modes	VREFL	—	VREFH		
C _{ADIN}	Input capacitance	16-bit mode	_	8	10	pF	
		 8-bit / 10-bit / 12-bit modes 	_	4	5		
R _{ADIN}	Input resistance		_	2	5	kΩ	
R _{AS}	Analog source	13-bit / 12-bit modes					3
	resistance	f _{ADCK} < 4 MHz	_	_	5	kΩ	
f _{ADCK}	ADC conversion clock frequency	≤ 13-bit mode	1.0		18.0	MHz	4
f _{ADCK}	ADC conversion clock frequency	16-bit mode	2.0	—	12.0	MHz	4

6.6.1.1 16-bit ADC operating conditions Table 24. 16-bit ADC operating conditions



Symbol	Description	Conditions ¹ .	Min.	Typ. ²	Max.	Unit	Notes
SFDR	Spurious free dynamic range	16-bit differential modeAvg = 32	82	95	_	dB	7
		16-bit single-ended modeAvg = 32	78	90	_	dB	
E _{IL}	Input leakage error			$I_{ln} \times R_{AS}$		mV	I _{In} = leakage current
							(refer to the MCU's voltage and current operating ratings)
	Temp sensor slope	Across the full temperature range of the device	1.55	1.62	1.69	mV/°C	8
V _{TEMP25}	Temp sensor voltage	25 °C	706	716	726	mV	8

Table 25. 16-bit ADC characteristics ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SSA}$) (continued)

- 1. All accuracy numbers assume the ADC is calibrated with $V_{REFH} = V_{DDA}$
- Typical values assume V_{DDA} = 3.0 V, Temp = 25 °C, f_{ADCK} = 2.0 MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
- The ADC supply current depends on the ADC conversion clock speed, conversion rate and ADC_CFG1[ADLPC] (low power). For lowest power operation, ADC_CFG1[ADLPC] must be set, the ADC_CFG2[ADHSC] bit must be clear with 1 MHz ADC conversion clock speed.
- 4. 1 LSB = $(V_{REFH} V_{REFL})/2^{N}$
- 5. ADC conversion clock < 16 MHz, Max hardware averaging (AVGE = %1, AVGS = %11)
- 6. Input data is 100 Hz sine wave. ADC conversion clock < 12 MHz.
- 7. Input data is 1 kHz sine wave. ADC conversion clock < 12 MHz.
- 8. ADC conversion clock < 3 MHz



rempheral operating requirements and behaviors

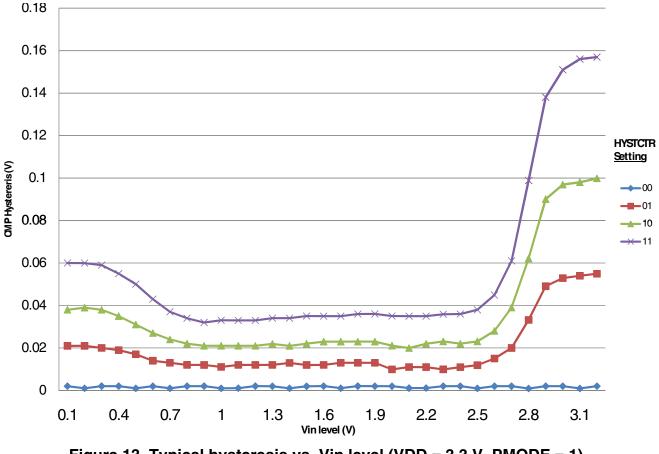


Figure 13. Typical hysteresis vs. Vin level (VDD = 3.3 V, PMODE = 1)

6.7 Timers

See General switching specifications.

6.8 Communication interfaces

6.8.1 USB electrical specifications

The USB electricals for the USB On-the-Go module conform to the standards documented by the Universal Serial Bus Implementers Forum. For the most up-to-date standards, visit **usb.org**.



6.8.2 USB DCD electrical specifications

Table 27. USB DCD electrical specifications

Symbol	Description	Min.	Тур.	Max.	Unit
V _{DP_SRC}	USB_DP source voltage (up to 250 µA)	0.5	—	0.7	V
V _{LGC}	Threshold voltage for logic high	0.8	—	2.0	V
I _{DP_SRC}	USB_DP source current	7	10	13	μA
I _{DM_SINK}	USB_DM sink current	50	100	150	μA
R _{DM_DWN}	D- pulldown resistance for data pin contact detect	14.25	—	24.8	kΩ
V _{DAT_REF}	Data detect voltage	0.25	0.33	0.4	V

6.8.3 VREG electrical specifications

Table 28. VREG electrical specifications

Symbol	Description	Min.	Typ. ¹	Max.	Unit	Notes
VREGIN	Input supply voltage	2.7	—	5.5	V	
I _{DDon}	Quiescent current — Run mode, load current equal zero, input supply (VREGIN) > 3.6 V	—	125	186	μA	
I _{DDstby}	Quiescent current — Standby mode, load current equal zero	—	1.1	10	μA	
I _{DDoff}	Quiescent current — Shutdown mode VREGIN = 5.0 V and temperature=25 °C Across operating voltage and temperature 	_	650 —	4	nA μA	
I _{LOADstby}	Maximum load current — Standby mode	_	—	1	mA	
V _{Reg33out}	Regulator output voltage — Input supply (VREGIN) > 3.6 V					
	Run mode Standby mode	3	3.3	3.6	v	
	Standby mode	2.1	2.8	3.6	V	
V _{Reg33out}	Regulator output voltage — Input supply (VREGIN) < 3.6 V, pass-through mode	2.1	_	3.6	V	2
C _{OUT}	External output capacitor	1.76	2.2	8.16	μF	
ESR	External output capacitor equivalent series resistance	1	-	100	mΩ	
I _{LIM}	Short circuit current		315	—	mA	

1. Typical values assume VREGIN = 5.0 V, Temp = 25 °C unless otherwise stated.

2. Operating in pass-through mode: regulator output voltage equal to the input voltage minus a drop proportional to ILoad.



Num	Description	Min.	Max.	Unit
DS10	DSPI_SCK input high/low time	(t _{SCK} /2) – 2	(t _{SCK} /2) + 2	ns
DS11	DSPI_SCK to DSPI_SOUT valid	—	10	ns
DS12	DSPI_SCK to DSPI_SOUT invalid	0	_	ns
DS13	DSPI_SIN to DSPI_SCK input setup	2	—	ns
DS14	DSPI_SCK to DSPI_SIN input hold	7	—	ns
DS15	DSPI_SS active to DSPI_SOUT driven	_	14	ns
DS16	DSPI_SS inactive to DSPI_SOUT not driven	—	14	ns

Table 30. Slave mode DSPI timing (limited voltage range) (continued)

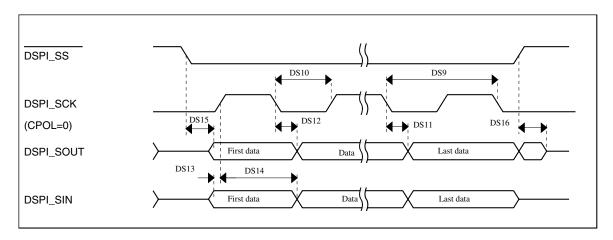


Figure 15. DSPI classic SPI timing — slave mode

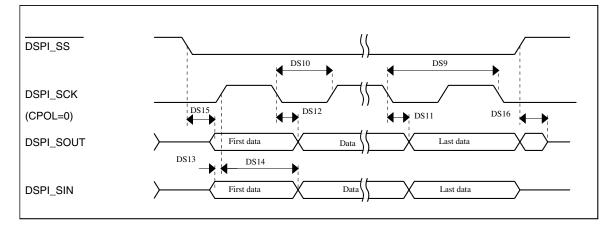
6.8.5 DSPI switching specifications (full voltage range)

The DMA Serial Peripheral Interface (DSPI) provides a synchronous serial bus with master and slave operations. Many of the transfer attributes are programmable. The tables below provides DSPI timing characteristics for classic SPI timing modes. Refer to the DSPI chapter of the Reference Manual for information on the modified transfer formats used for communicating with slower peripheral devices.

Num	Description	Min.	Max.	Unit	Notes
	Operating voltage	1.71	3.6	V	1
	Frequency of operation	—	12.5	MHz	
DS1	DSPI_SCK output cycle time	4 x t _{BUS}	_	ns	
DS2	DSPI_SCK output high/low time	(t _{SCK} /2) - 4	(t _{SCK/2)} + 4	ns	
DS3	DSPI_PCSn valid to DSPI_SCK delay	(t _{BUS} x 2) – 4	_	ns	2

Table 31. Master mode DSPI timing (full voltage range)







6.8.6 I²C switching specifications

See General switching specifications.

6.8.7 UART switching specifications

See General switching specifications.

6.8.8 Normal Run, Wait and Stop mode performance over the full operating voltage range

This section provides the operating performance over the full operating voltage for the device in Normal Run, Wait and Stop modes.

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S1	I2S_MCLK cycle time	40	_	ns
S2	I2S_MCLK (as an input) pulse width high/low	45%	55%	MCLK period
S3	I2S_TX_BCLK/I2S_RX_BCLK cycle time (output)	80	—	ns
S4	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low	45%	55%	BCLK period
S5	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output valid	—	15	ns
S6	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output invalid	0	_	ns
S7	I2S_TX_BCLK to I2S_TXD valid	—	15	ns

Table 33. I2S/SAI master mode timing



Num.	Characteristic	Min.	Max.	Unit
S8	I2S_TX_BCLK to I2S_TXD invalid	0	—	ns
S9	I2S_RXD/I2S_RX_FS input setup before I2S_RX_BCLK	25	_	ns
S10	I2S_RXD/I2S_RX_FS input hold after I2S_RX_BCLK	0		ns



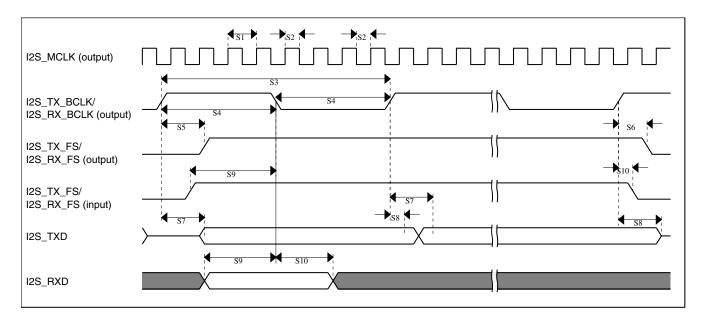


Figure 18. I2S/SAI timing — master modes

Table 34. I2S/SAI slave mode timing

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S11	I2S_TX_BCLK/I2S_RX_BCLK cycle time (input)	80	—	ns
S12	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low (input)	45%	55%	MCLK period
S13	I2S_TX_FS/I2S_RX_FS input setup before I2S_TX_BCLK/I2S_RX_BCLK	10	_	ns
S14	I2S_TX_FS/I2S_RX_FS input hold after I2S_TX_BCLK/I2S_RX_BCLK	2	_	ns
S15	I2S_TX_BCLK to I2S_TXD/I2S_TX_FS output valid	—	29	ns
S16	I2S_TX_BCLK to I2S_TXD/I2S_TX_FS output invalid	0	—	ns
S17	I2S_RXD setup before I2S_RX_BCLK	10	_	ns
S18	I2S_RXD hold after I2S_RX_BCLK	2	—	ns
S19	I2S_TX_FS input assertion to I2S_TXD output valid ¹	—	21	ns

1. Applies to first bit in each frame and only if the TCR4[FSE] bit is clear



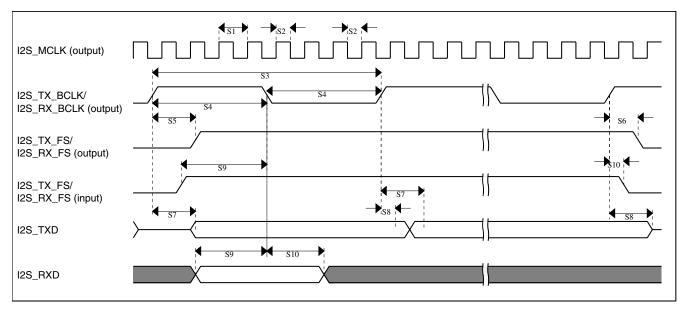


Figure 20. I2S/SAI timing — master modes

Table 36. I2S/SAI slave mode timing in VLPR, VLPW, and VLPS modes (full voltage range)

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S11	I2S_TX_BCLK/I2S_RX_BCLK cycle time (input)	250	_	ns
S12	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low (input)	45%	55%	MCLK period
S13	I2S_TX_FS/I2S_RX_FS input setup before I2S_TX_BCLK/I2S_RX_BCLK	30	_	ns
S14	I2S_TX_FS/I2S_RX_FS input hold after I2S_TX_BCLK/I2S_RX_BCLK	2	_	ns
S15	I2S_TX_BCLK to I2S_TXD/I2S_TX_FS output valid	_	87	ns
S16	I2S_TX_BCLK to I2S_TXD/I2S_TX_FS output invalid	0	—	ns
S17	I2S_RXD setup before I2S_RX_BCLK	30	_	ns
S18	I2S_RXD hold after I2S_RX_BCLK	2	_	ns
S19	I2S_TX_FS input assertion to I2S_TXD output valid ¹	—	72	ns

1. Applies to first bit in each frame and only if the TCR4[FSE] bit is clear





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